

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Massimo CIVILINI

Serial No.:

Group Art Unit:

Filed: 6/24/03

Examiner:

Title: AN ELECTRONIC COMPONENT RELIABILITY DETERMINATION SYSTEM AND METHOD

The Commissioner of Patents and Trademarks
P.O. Box 1450
Alexandria, VA 22313-1450
Sir:

Information Disclosure Statement Submitted Pursuant to 37 C.F.R. 1.97(b)

The citations referenced herein, copies attached, may be material to the examination of the above-identified application and are, therefore, submitted in compliance with the duty of disclosure as defined in 37 C.F.R. 1.56. The Examiner is requested to make these citations of official record in the application.

This Information Disclosure Statement submitted in accordance with 37 C.F.R. 1.97(b) is not to be construed as a representation that a search has been made, that additional items material to the examination of this application do not exist, or that any one or more of these citations constitute prior art under 35 U.S.C. 102.

The Examiner's attention is respectfully directed to the following documents:

<u>Title</u>	<u>Publication Date</u>
"SRAM Module; Mean Time Between Failure Analysis (MTBF)," Hybrid Memory Products LTD, 11 pages	February 1999
"Reliability Prediction of Board-Mounted Power Modules," Tyco Electronics, Technical Note, 6 pages	July 1997
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Please direct all correspondence concerning the above-identified application to the following address:

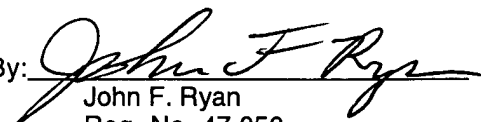
WAGNER, MURABITO & HAO LLP
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Respectfully submitted,

Date:

6/24/03

By:


John F. Ryan
Reg. No. 47,050

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Form 1449**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	L							
	M							
	N							
	O							
	P							
	Q							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	"SRAM Module; Mean Time Between Failure Analysis (MTBF)," Hybrid Memory Products LTD, February 1999, 11 pages
	S	"Reliability Prediction of Board-Mounted Power Modules," Tyco Electronics, Technical Note, July 1997, 6 pages
	T	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered.
 Include copy of this form with next communication to applicant.